oratory	Gee Kay Engineering,103-C, Gokul Galaxy, Thakur Complex, Kandivali (E), Mumbai, Maharashtra						
reditation Standard	ISO/IEC 17025: 2005						
tificate Number	CC-2665 (In lieu of C-015	56) Page	1 of 2				
idity	14.06.2018 to 13.06.2	2020 Last Ame	Last Amended on -				
Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability (±)	Remarks				
MECHANICAL CALIBRATION							
DIMENSION (BASIC MEASURING INSTRUMENT, GAUGE ETC.)							
Surface Plate [*] Flatness L.C. 1µm/m Base Length 125 mm L.C. 1µm/m Base Length 225 mm	1000 mm x 1000 mm Above 1000 mm x 1000 mm	$0.4 \times \sqrt{\frac{L+W}{100}}$ $0.7 \times \sqrt{\frac{L+W}{200}}$ L & W in mm	Using Electronic Level by Comparison Method as per IS 12937				
L.C. 20µm/m Base Length 125 mm L.C. 20µm/m Base Length 225 mm	1000mm x 1000 mm Above 1000 mm x 1000 mm	$2.4 \times \sqrt{\frac{L+W}{100}}$ $4.3 \times \sqrt{\frac{L+W}{200}}$	Using Precision Level by Comparison Method as per IS 12937				
	reditation Standard tificate Number dity Quantity Measured / Instrument DIMENSION (BASIC M Surface Plate* Flatness L.C. 1µm/m Base Length 125 mm L.C. 1µm/m Base Length 225 mm L.C. 20µm/m Base Length 125 mm	Kandivali (E), Mumbareditation StandardISO/IEC 17025: 2005tificate NumberCC-2665 (In lieu of C-018)dity14.06.2018 to 13.06.2Quantity Measured / InstrumentRange/FrequencyQuantity Measured / InstrumentRange/FrequencyDIMENSION (BASIC MEASURING INSTRUME)Surface Plate* Flatness L.C. 1µm/m Base Length 125 mm1000 mm x 1000 mmL.C. 1µm/m Base Length 225 mmAbove 1000 mm x 1000 mmL.C. 20µm/m Base Length 125 mm1000 mm x 1000 mmL.C. 20µm/m Base Length 125 mm1000 mm x 1000 mmL.C. 20µm/m Base Length 125 mm1000 mm x 1000 mm	Kandivali (E), Mumbai, Maharashtrairreditation StandardISO/IEC 17025: 2005tificate NumberCC-2665 (In lieu of C-0156)Pagedity14.06.2018 to 13.06.2020Last AmeQuantity Measured / InstrumentRange/Frequency*Calibration Measurement Capability (±)MECHANICAL CALIBRATIONDIMENSION (BASIC MEASURING INSTRUMENT, GAUGE ETC.)Surface Plate* Flatness L.C. 1µm/m Base Length 125 mm1000 mm x 1000 mm0.4 x $\sqrt{\frac{L+W}{100}}$ L.C. 1µm/m Base Length 225 mm1000 mm x 1000 mm0.7 x $\sqrt{\frac{L+W}{200}}$ L & W in mmL.C. 20µm/m Base Length 125 mm1000mm x 1000 mmL.C. 20µm/m Base Length 125 mm1000mm x 1000 mm $2.4 \times \sqrt{\frac{L+W}{100}}$				

LaboratoryGee Kay Engineering,103-C, Gokul Galaxy, Thakur Complex,
Kandivali (E), Mumbai, MaharashtraAccreditation StandardISO/IEC 17025: 2005

Certificate Number	CC-2665 (In lieu of C-0156)	Page	2 of 2
Validity	14.06.2018 to 13.06.2020	Last Amended on	-

SI.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability (±)	Remarks
2.	Box Angle Plate / Angle Plate [*] Flatness L.C. 20µm/m; Base Length 125 mm	450mm x300mm x 350 n		Using Precision Level by Comparison Method
	Parallelism Squareness			Using Gauge Block Dial Indicator L.C.1µm by Comparison Method
3.	Straight Edge*			
	Straightness L.C. 20µm/m; Base Length 125 mm L.C. 20µm/m; Base Length 225 mm	Up to 1000 mm Above 1000 mm		Using Precision Level by Comparison Method
4.	Parallelism *	Up to 1000 mm Above 1000 mm		Using Gauge Block Dial Indicator L.C.1µm & Surface Plate by Comparison Method
5.	Bench Centre [*] Co – Axiality	300 mm to 1500 mm	5.6 x $\sqrt{\frac{E \max}{300}}$ H in mm	Using Taper Mandrel; Plain Mandrel & Dial Indicator L.C.1µm
	Parallelism		5.8 mm	

* Measurement Capability is expressed as an uncertainty (±) at a confidence probability of 95% *Only for Site Calibration